

United States Patent and Trademark Office

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.usplo.gov

		CLO CON LLA LED DAVIENTO			
APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/628,626	07/28/2003	Evan R. Mapoles	58159.US	5819	
60838 75	90 05/03/2006		EXAM	INER	
LNG/KLA JOINT CUSTOMER			NGUYEN, TU T		
C/O LUEDEK A	A, NEELY & GRAHAM	1, P.C.			
P.O. BOX 1871			ART UNIT	PAPER NUMBER	
KNOXVILLE,	TN 37901		2877		

DATE MAILED: 05/03/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)	
		10/628,626	MAPOLES ET AL.	
	Office Action Summary	Examiner	Art Unit	
		Tu T. Nguyen	2877	_
Period f	The MAILING DATE of this communication for Reply	appears on the cover sheet w	ith the correspondence address	
WHI - Extended aftended - If N - Fail Any	HORTENED STATUTORY PERIOD FOR REL CHEVER IS LONGER, FROM THE MAILING ensions of time may be available under the provisions of 37 CFR er SIX (6) MONTHS from the mailing date of this communication. O period for reply is specified above, the maximum statutory per lure to reply within the set or extended period for reply will, by star or reply received by the Office later than three months after the manned patent term adjustment. See 37 CFR 1.704(b).	DATE OF THIS COMMUNI 1.136(a). In no event, however, may a iod will apply and will expire SIX (6) MOI atute, cause the application to become A	CATION. reply be timely filed ITHS from the mailing date of this communicatio BANDONED (35 U.S.C. § 133).	
Status				
1)	Responsive to communication(s) filed on		•	•
2a)[_	This action is FINAL . 2b)⊠ T	his action is non-final.		
3)[Since this application is in condition for allo	wance except for formal mat	ters, prosecution as to the merits is	S
	closed in accordance with the practice unde	er <i>Ex parte Quayle</i> , 1935 C.[). 11, 453 O.G. 213.	
Disposi	tion of Claims		•	
4)🛛	Claim(s) 1-20 is/are pending in the application	on.		
	4a) Of the above claim(s) is/are without	drawn from consideration.		
5)[Claim(s) is/are allowed.			
,	Claim(s) <u>1-20</u> is/are rejected.			
• —	Claim(s) is/are objected to.			
8)∟	Claim(s) are subject to restriction an	d/or election requirement.		
Applica	tion Papers			
9)[The specification is objected to by the Exam	iner.		
10)⊠	The drawing(s) filed on 28 July 2003 is/are:			
	Applicant may not request that any objection to			
	Replacement drawing sheet(s) including the cor			(d)
11)	The oath or declaration is objected to by the	Examiner. Note the attache	d Office Action or form P1O-152.	
Priority	under 35 U.S.C. § 119			
12)	Acknowledgment is made of a claim for fore	ign priority under 35 U.S.C.	§ 119(a)-(d) or (f).	
а	ı)			
	1. Certified copies of the priority docum	•		
	2. Certified copies of the priority docum			
	3. Copies of the certified copies of the p		received in this National Stage	
	application from the International Bur			
•	See the attached detailed Office action for a	list of the certified copies no	received.	
Attachme	ent(s)			
1) 🔀 Not	ent(s) tice of References Cited (PTO-892) tice of Draftsperson's Patent Drawing Review (PTO-948)	· —	Summary (PTO-413) (s)/Mail Date	

U.S. Patent and Trademark Office PTOL-326 (Rev. 7-05)

Paper No(s)/Mail Date <u>07/28/2003</u>.

6) Other: ____.

DETAILED ACTION

Claim Objections

Claim 10 is objected to because of the following informalities:

1) Claim 10, line 1, "the method of claim 8" should be changed to "the method of claim 9".

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1-20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Applicant Admitted Prior Art (Specification, pages 2-15) (AAPA hereinafter) in view of Jasper et al (6,674,510) and Finarov (6,038,029).

With respect to claims 1,9-10, AAPA disclose an integrated inspection system adapted to inspect a substrate. The inspection system comprising: a first inspection station adapted to perform a first inspection of the substrate at a first resolution and for identifying defect candidate sites (AAPA, page 2, lines 20-24), a second inspection station adapted to perform a second inspection of the defect candidate sites at a second resolution, where the second resolution is higher than the first resolution (AAPA, page 2, lines 25-28; page 3, lines 1-8).

Art Unit: 2877

0077

AAPA does not explicitly disclose the first inspection station disposed at a first known location, a second station disposed at a second known location, a controller, a substrate stage adapted to move the substrate between the first known location of the first inspection station and the second known location of the second inspection station.

Jasper discloses a system for inspecting a substrate. The system comprises: a substrate stage (column 2, lines 58-62) adapted to move the substrate between the first known location of the first inspection station and the second known location of the second inspection station (column 6, lines 35-42, Jasper discloses that the stage could be used for multiple measurement stations), a controller (a position system, column 2, line 58). It would have been obvious to modify AAPA with the substrate stage and a controller taught by Jasper to facilitate the measuring.

Jasper does not explicitly disclose a stage to move the substrate under both inspection stations. Finarov discloses a stage 110 (fig 7A) for moving the substrate under different measuring systems. It would have been obvious to modify Jasper stage with the stage taught by Finarov to perform different measuring processes without transferring the substrate to reduce loss of accuracy as taught by Finarov in column 2, lines 10-25).

With respect to claims 2-3, AAPA discloses using an optical inspection system for the first station and a microscope for a second station (Specification, page 2, last paragraph and page 3, first paragraph).

Application/Control Number: 10/628,626

Art Unit: 2877

With respect to claims 4-7,11-14,18-20, the claimed microscopes would have been known. It would have been obvious to modify AAPA with different types of microscope for different measuring purposes.

With respect to claims 8,15, Jasper does not explicitly disclose the distance between the stations. However, according to fig 8, the distance between the stations 20a and 10 seems to be fixed. Further, It would have been obvious to modify Jasper by having a known distance between the stations in order to move the substrate between the stations easier.

With respect to claim 16, refer to discussion in claim 1 above for the system.

Further, AAPA discloses classifying the defects by the second system (page 2, lines 25-28).

With respect to claim 17, refer to discussion claim 1 above for the controller.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tu T. Nguyen whose telephone number is (571) 272-2424. The examiner can normally be reached on T-F 7:30-5:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Gregory Toatley Jr. can be reached on (571) 272-2800 Ext. 77. The fax

Application/Control Number: 10/628,626

Art Unit: 2877

phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

> Tu T. Nguyen **Primary Examiner** Art Unit 2877

Page 5

04/25/2006